



Abel Haro Armero

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ABOUT ME

Computer Engineering student, currently in the fourth year. Possess a strong theoretical foundation and technical skills in software development and problem-solving. Quick learner, team player, and adept at facing challenges with creativity and determination.

EDUCATION

- **Universitat Politècnica de València** 2021 - present
Computer Engineering average grade 8.4

LANGUAGES

Spanish - Native
English - B2

PROFESSIONAL EXPERIENCE

- **Internship at the DISCA Department, UPV** October 2024 - Present
Universitat Politècnica de València
 - Developed a system for detecting defects in objects from images using neural networks.
- **Internship at SOLTECSIS S.L.** July 2024
SOLTECSIS S.L.
 - Performed debugging and bug fixing during the migration of the open-source FWCloud project from JavaScript to TypeScript.

PERSONAL AND STUDENT PROJECTS

- **DescubreUPV** May 2025
Project for the DADM (Mobile Device Application Development) subject.
 - Tools & technologies used: Kotlin, Android Studio, Supabase.
 - The goal of the application is to help new students get to know the university, its facilities, and services. To achieve this, the application features an interactive map that allows users to explore the university and find information about different buildings and services.
 - The application is developed in Kotlin and uses Android Studio as the development environment. Additionally, Supabase has been used as the backend to store and manage information about locations and users.
- **Defect detection in objects using convolutional neural networks** October 2024 - June 2025
Final Degree Project in Computer Engineering.
 - Developed a system for detecting defects in objects from images using convolutional neural networks. Utilized the Ultralytics framework for training and deploying YOLO models, which were optimized for NVIDIA Jetson hardware with the TensorRT SDK. The system enables real-time defect detection and image analysis for identifying defects in industrial products.